Comparision of optical properties of spun cast polystyrene and iodine doped polystyrene films

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In the present work the optical properties polystyrene and iodine doped polystyrene films has been studied. Thin films of polystyrene and iodine doped polysterene were deposited on glass substrates by spin coating technique at 2000 rpm for 30s. Thin films were characterized by X-ray diffraction technique to check their amorphous nature. The basic optical properties of spun cast thin films were analyzed using their transmission spectra. The related parameters i.e. oscillator strength (E_0), dispersion energy (E_d) were determined by the Wemple-Didomenico single oscillator model. The refractive index (n), extinction coefficient (k) and dielectric constants of thin films were calculated. The optical band gap was calculated by Tauc's extrapolation and is 1.19 eV and 2.14 eV for the polystyrene and iodine doped polystyrene thin films respectively. It has been found that both optical band gap and refractive index increases with the addition of iodine.

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1. Introduction

Polymers are emerging as an important class of materials, which offers challenging opportunities for both fundamental research and new technological applications. The important advantage of polymers lies in their structural flexibility both at molecular and bulk levels. Polymer thin film coatings on solid substrates are of high technological importance due to their increasing potential of applications in electronics, sensors etc. These coatings are commonly used to optically match the refractive index of lenses and minimize reflections in optical components. In order for these coatings to be effective it is important to determine their optical constants with high accuracy. It is well established that stress can affect the optical properties of polymer thin films. Previous studies by Prest [1,2] and coworkers [3,4], have shown that spinning and solvent casting processes can induce stress in polymer thin films.

Polystyrene is chemically inert and resistant to oxidizing and reducing agents. It has excellent optical properties like color, chirality and high refractive index (1.60). These properties led us to fabricate polystyrene thin film that can be used as optical wave-guides with low propagation losses. In the field of optical devices polymers are very effective for creating complex integrated optical devices. The optical study to calculate refractive index (n) and extinction coefficient (k) was performed for polystyrene thin film and compared with iodine doped polystyrene thin film by analyzing transmission spectrum using envelop method proposed by Swanepoel [5]. So, the aim of present study is to determine the effect of iodine doping on optical properties of spun cast polystyrene thin film.

2. Experimental details

2.1 Preparation of polystyrene thin film

In this study polystyrene was prepared as follows: Styrene monomer was taken and polymerized by bulk polymerization technique. 50 mg of freshly recrystallized dry initiator benzoyl peroxide (BPO) was taken, and 10 ml of styrene monomer was added to it in a conical flask. The flask was stirred gently till the BPO got fully dissolved in the monomer. Another 40 ml of styrene and 500 mg of dodecvl merceptane (DDM) chain modifier were then added to the flask and the contents were flushed with oxygen free dry nitrogen for about 15 minutes. A water condenser was then fitted to the flask and the flask was then fitted placed in a constant temperature bath maintained at 70°C. The flask was then stirred after every five minutes. Then the viscosity increase was constantly observed and the flask was removed from the bath when the contents attained high viscosity. These were then emptied from the flask in 250 ml of toluene taken in a beaker. The contents of the beaker were now stirred for some time with a glass rod; till a homogeneous solution was formed. Polystyrene formed was now in the form of a solution in a mixture of toluene and the remaining styrene monomer. The polystyrene so formed was recovered by pouring the solution slowly into 2 liters of methanol under constant agitation. Polymer then precipitated as white fluffy solid. The solid polymer was then again washed with methanol and dried at 60°C. The film of polystyrene was prepared from viscous saturated solution analar grade toluene. The thin films of polystyrene and iodine doped polystyrene were casted on borosilicate substrate (microscopic glass slide) using spin coating technique for

thin film fabrication, by spinning the substrate at 2000 rpm for 30 s. Then the film was dried in air. The film was then dried at 40°C for three hours. From the optical spectral curves, the average thickness of the films was calculated [6] and found to be 1900 nm and 2200 nm for polystyrene and iodine doped polystyrene films. The properties related to structure were studied by using microscopic (SEM, NMR) methods.



(a)

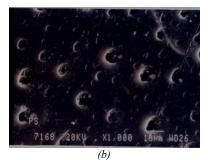
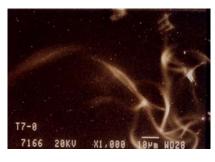


Fig. 1. SEM images of polystyrene sample at different magnifications.



(a)

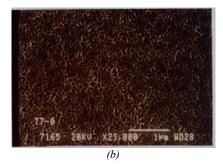


Fig. 2. SEM images of polystyrene thin film at different magnifications.

2. 2 Measurements

¹H NMR, SEM (Fig. 1 and 2) analysis was performed to get an idea about the configuration, conformation, sequence distribution and tacticity of polystyrene chains. The UV-Visible spectra of the polystyrene thin film was recorded by Perkin Elmer Lamda 750 UV/Visible/NIR spectrophotometer at room temperature. The optical transmission spectrum was analyzed to calculate the optical constants such as refractive index (*n*) and extinction coefficient *k*. Analysis of absorption coefficient was also carried out to determine optical band gap of the polystyrene and iodine doped polystyrene thin films.

2. 3 Characterization studies

In the ¹H NMR spectra the doublets at 5.77 & 5.71 and 5.25 & 5.25 were due to unsaturated chain ends present in the polymer chain. The two broad peaks at 1.63 and 1.42 correspond to the protons of CH and CH₂ of polystyrene. Up field peak having high relative intensity is ascribed to CH₂ and down field with low relative intensity is due to former. In the extended spectra of polystyrene in the region between 5.0 and 7.6, two peaks one at 7.03 and other at 6.57 were found due to the fact that the orthoprotons of benzene are in different environment and other protons were in different one that explains splitting of the signal.

NMR of polystyrene was compared with literature reference and it is similar to the reported spectra of isotactic polystyrene implying that the polystyrene under investigation in the present work has high tacticity with isotactic and syndotactic conformations of phenyl ring.

3. Results and discussion

3.1 Refractive index and extinction coefficient

Using the experimental data of optical transmittance of the polystyrene and iodine doped polystyrene thin films; the refractive index and extinction coefficient were calculated. The homogeneous films has thickness (d) and complex refractive index $n^* = n - k$, where n is the refractive index and k is the extinction coefficient. The thickness of the substrate is several times the thickness of the film. Fig. 3 shows the oscillating curves which indicate that the thickness of the films is constant.

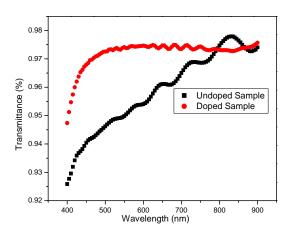


Fig. 3. Transmission spectra of polystyrene and iodine doped polystyrene films.

The optical parameters were obtained from the fitting pattern in transmittance spectrum. According to Swanepoel [5] the value of refractive index can be calculated as follows:

$$n = [N + (N^2 - \kappa^2)^{\frac{1}{2}}]^{\frac{1}{2}}$$
 (1)

where

$$N = \frac{2s}{T_{\text{m}}} - \frac{(s^2 + 1)}{2} \tag{2}$$

and T_m is the envelope function of minimum transmittance and s is the refractive index of the substrate.

In the weak region where $\alpha \neq 0$ the transmittance decreases due to influence of α and refractive index is given by

$$n = \left[M + (M^2 - s^2)^{\frac{1}{2}}\right]^{\frac{1}{2}} \tag{3}$$

Where

$$M = 2s \frac{T_M - T_m}{T_M T_m} + \frac{(s^2 + 1)}{2}$$
(4)

and T_{M} is the envelope function of maximum transmittance. Refractive index can be calculated by extrapolating the envelops corresponding to T_{M} and T_{m}

The extinction coefficient k can be calculated using the relation

$$\ddot{k} = \frac{\alpha \lambda}{4\pi} \tag{5}$$

where α is the absorption coefficient.

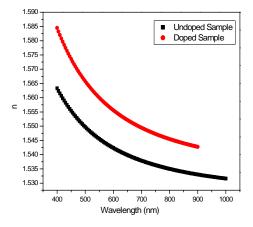


Fig. 4. Variation of extinction coefficient with wavelength for polystyrene and iodine doped polystyrene films.

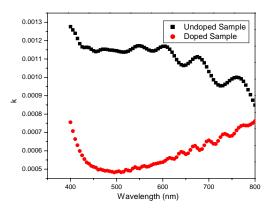


Fig. 5. Variation of refractive index with wavelength for polystyrene and iodine doped polystyrene films.

The spectral distributions of refractive index and extinction coefficient are shown in Fig. 4 and Fig. 5 respectively. Refractive index was found to decrease with increase of wavelength for both polystyrene and iodine doped thin films. For iodine doped thin film refractive index has higher values than undoped film. The higher value for iodine doped film is attributed to the interaction between unsaturated ends of polystyrene and iodine. The refractive index changes with the variation of wavelength of incident beam due to interaction between photon and electrons [7]. The extinction coefficient values are found to be of the order of 10^{-4} . It has been found that the values of k are smaller for iodine doped films shows that optical losses are small than undoped film. The very low values k also confirm the homogeneity of films.

The spectral dispersion of refractive index has been studied using Wemple-DiDomenico single oscillator model [8-10]:

$$n^2 - 1 = \frac{E_0 E_0}{E_0^2 - (hv)^2} \tag{6}$$

where n is the refractive index, h is Planck's constant, v is the frequency, hv is the photon energy, E_o is the average excitation energy for electronic transitions and E_d is the dispersion energy which is a measure of strength of interband optical transitions. The dielectric response for transitions below the optical gap is described by this model. E_d and $E_o[9]$ values were calculated from the slope and intercept on the vertical axis of plot of $v^2 - v^2$ (Fig. 6) and are given in the Table 1.

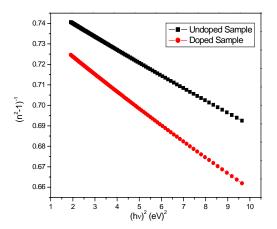


Fig. 6. Plot of $(n^2-1)^{-1}vs$. $(hv)^2$ $(eV)^2$ for polystyrene and iodine doped polystyrene films.

Table 1. Optical parameters of polystyrene and iodine doped polystyrene films.

Sample	Eg Optical band gap [eV]	E Oscillator strength [eV]	Dispersion energy [eV]
Polystyrene	1.19	10.93	14.54
Iodine doped polystyrene	2.14	12.30	15.87

3. 2 Determination of optical band gap

To determine the nature of the optical transitions, the optical transmission study was performed for the thin films. In the region of high absorption from which optical band gap is determined, the absorption is characterized by Tauc's relation [11]

$$\alpha h v = B(h v - E_g)^n \tag{7}$$

where hv, r and r denotes the photon energy, the optical gap and band tailing parameter respectively and r is a constant which determines the type of transition ($r = \frac{1}{2}$ and r direct allowed and forbidden transitions respectively, r = 2 and 3 for indirect allowed and forbidden transitions respectively). The value of r was calculated from the curve of r versus r and was found to be 2 which show an indirect transition. More precise value was obtained from the linear part of r versus r curve (figure 7) and is given in table 1. It is found that with the addition of iodine the optical band gap increases significantly due to interaction between iodine and unsaturated ends of polystyrene chains.

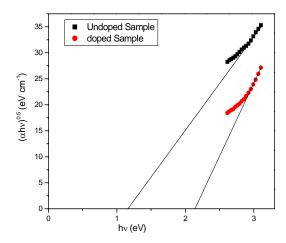


Fig. 7. Plot of $(ahv)^{0.5}$ vs. photon energy for polystyrene and iodine doped polystyrene films.

3. 3 Complex dielectric function

The complex dielectric constant of a solid material. The real and imaginary parts of dielectric constant were also calculated by the following relation [12]:

$$T_r = n^* - K^* \tag{8}$$

and

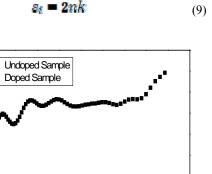


Fig. 8. Plot of ε_i vs. photon energy for polystyrene and iodine doped polystyrene films.

Photon energy (eV)

20 22 24 26 28 3.0

0.0042

0.0040

0.0038

0.0036

0.0034

0.0032

0.0030

0.0028

0.0026 0.0024 0.0022

0.0020

0.0016

0.0014

1.6

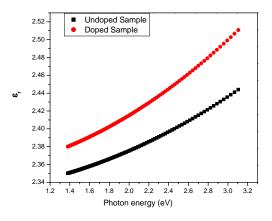


Fig. 9. Plot of ε_r vs. photon energy for polystyrene and iodine doped polystyrene films.

The real and imaginary parts of the dielectric constant were calculated by using eqn. (8) and (9) are shown in Figs. 8 and 9, respectively. It is seen that real and imaginary parts of the dielectric constant increases with increase in photon energy for polystyrene thin film, but for iodine doped thin films the value of the real part is larger compared to that of undoped thin film and the imaginary part of dielectric constant decreases with the increase in photon energy.

The transmission spectra of polystyrene and iodine doped polystyrene thin films were analyzed to calculate the optical parameters. Refractive index increases and extinction coefficient first decreases then at a certain point it also start increasing increase in wavelength. The optical band gap was calculated by Tauc's extrapolation and is 1.19 eV and 2.14 eV for the polystyrene and iodine doped polystyrene thin films, respectively. The optical band gap calculated by the optical transmission spectra shows an increase with addition of iodine content. The oscillator energy E_o , dispersion energy E_d were determined by Wemple-Didomenico method.

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